

Electronic Patent Application Fee Transmittal				
Application Number:	10773524			
Filing Date:	06-Feb-2004			
Title of Invention:	Defect inspection apparatus and defect inspection method			
First Named Inventor/Applicant Name:	Takashi Yoneyama			
Filer:	Douglas Holtz/David Dunbar			
Attorney Docket Number:	04083/LH			
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Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
Basic Filing:				
Pages:				
Claims:				
Miscellaneous-Filing:				
Petition:				
Patent-Appeals-and-Interference:				
Post-Allowance-and-Post-Issuance:				
Extension-of-Time:				

Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
Miscellaneous:				
Request for continued examination	1801	1	810	810
Total in USD (\$)				810